

SUITE A1

SUNNYVALE, CA 94087

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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/791,095	03/01/2004	Yong Gang Jin	27-067.D1	27-067.D1 2465	
22898	7590 08/06/2004		EXAMINER		
THE LAW OFFICES OF MIKIO ISHIMARU			NGUYEN, THANH T		
1110 SUNNYVALE-SARATOGA ROAD		D	ART UNIT	PAPER NUMBER	

DATE MAILED: 08/06/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
Office Action Commons	10/791,095	JIN ET AL.	: :		
Office Action Summary	Examiner	Art Unit			
	Thanh T. Nguyen	2813			
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence add	dress		
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	nely filed s will be considered timely the mailing date of this co D (35 U.S.C. § 133).			
Status					
1) Responsive to communication(s) filed on			:		
, ,	action is non-final.				
3)☐ Since this application is in condition for allowar			merits is		
closed in accordance with the practice under E	Ex parte Quayle, 1935 C.D. 11, 45	i3 O.G. 213.	:		
Disposition of Claims					
4)⊠ Claim(s) <u>30-45</u> is/are pending in the application	2				
4a) Of the above claim(s) is/are withdraw					
5) Claim(s) is/are allowed.	m nom consideration.		•		
6)⊠ Claim(s) <u>30-45</u> is/are rejected.					
7) Claim(s) is/are objected to.					
8) Claim(s) are subject to restriction and/o	r election requirement.		:		
Application Papers					
9) The specification is objected to by the Examine	r.				
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.					
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).					
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).					
11) The oath or declaration is objected to by the Ex	aminer. Note the attached Office	Action or form PT	O-152.		
Duineitu undar 25 II C C C 440			•		
Priority under 35 U.S.C. § 119			:		
12) Acknowledgment is made of a claim for foreign	priority under 35 U.S.C. § 119(a)	-(d) or (t).			
a) ☐ All b) ☐ Some * c) ☐ None of:					
1. Certified copies of the priority documents		on No	- -		
2. Certified copies of the priority documents3. Copies of the certified copies of the priority			: Stago		
application from the International Bureau		zu III tilis Ivational	Stage : :		
* See the attached detailed Office action for a list	* **	.			
	от на объщно вория на объем н		•		
Attachment(s)					
1) Notice of References Cited (PTO-892) 4) Interview Summary (PTO-413)					
2) Notice of Draftsperson's Patent Drawing Review (PTO-948) Paper No(s)/Mail Date					
Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	6) Other:	аселс Аррисацоп (РТС	-192) 		

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DETAILED ACTION

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 30-31, 36, 41-42 are rejected under 35 U.S.C. 102(e) as being anticipated by Chiu et al. (U.S. Patent No. 6,586,322).

Referring to figures 3a-3k, Chiu et al. teaches a method for the creation of a torch bump comprising he steps of:

a substrate (12), the substrate having been provided with a contact pad (15) over the surface thereof, a patterned and etched layer of passivation (14) having been deposited over the substrate, exposing the contact pad, a layer of UBM (16) having been blanket deposited over the layer of passivation including the exposed surface of the contact pad,

a base of the torch bump(26/28) having been created overlying the contact pad using a pattern and developed first layer of dry film (38) as a mask,

a layer of solder (30) of the torch bump having been created overlying the base using a patterned and developed second layer of dry film as a mask (22),

the patterned and developed first and second layers of dry film have been removed (see figure 3J), and

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reflow having been applied to the layer of solder (see figure 3J, col. 9, lines 62-64).

Regarding to claim 31, the base of the torch bump having been created comprising:

A first layer of dry film (38) having been deposited over the surface of the layer of UMB;

The first layer dry film (38) having been patterned and developed, having created an opening (24) through the first layer of dry that aligned with the contact pad, having created a first mask of dry film, exposing the layer of UMB (16, see figure 3F); and

Successive layer of the metal (26/28/30) having been deposited over the exposed surface of the layer of UMB in accordance with the opening created through the first mask of dry film (see figures 3F-3H).

Regarding to claim 36, the layer of solder having been created by:

A second layer of dry film (22) having been deposited over the surface of the first layer of dry film (38) thereby including the surface of the base (16),

The second layer of dry film (22) having been patterned and developed, having created an opening through the second layer of dry film that aligns with the base of the torch bump, having created a second mask of dry film, having exposed the base of the torch bump (see figures 3E-3F), and

A layer of solder (26/28/30) having been developed in accordance with the opening created through the second mask of dry film (22).

Regarding to claim 41, additionally the layer of UMB having been etched using the created base of the torch bump and the created layer of the solder as a mask (see figures 3I-3J).

Regarding to claim 42, etching the layer of UBM comprising a wet etching process the term "wet etching process" is method recitations in a device claimed, and they are non-limiting,

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because only the final product is relevant, not the method of making. A product by process claim is directed to the product per se, no matter how actually made. See also MPEP 2113. Moreover, an old or obvious product produced by a new method is not a patentable product, whether claimed in "product by process" claims or not.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-2, 4-29, 46-52 are rejected under 35 U.S.C. 103(a) as being unpatentable over Chiu et al. (U.S. Patent No. 6,586,322) as applied to claims 30-31, 36, 41-42 above in view of the Admitted Prior Art of the Present Invention (pages 15-16) and Rinne (U.S. Patent No. 6,492,197).

Chiu et al. teaches all of the limitations as described in the claimed invention above.

However, the reference does not teach the layer of UBM comprising nickel, forming a gold layer over the nickel layer, forming a solder layer of eutectic solder paste, and the thickness of the layers and the specific thickness and diameter of layer.

The Admitted Prior Art teaches forming layer of UBM comprising nickel (18, see page 4-5), a base of the solder ball comprising a layer of copper, a layer of nickel, followed by a layer of gold (pages 5-6).

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Therefore, it would have been obvious to a person of ordinary skill in the requisite art at the time of the invention was made would form a base of the solder ball comprising a layer of copper, a layer of nickel, followed by a layer of gold in process of Chiu et al. as taught by the Admitted Prior Art because the process is known in the art to create a solder ball

Rinne teaches forming a solder layer by using eutectic solder paste (see abstract).

Therefore, it would have been obvious to a person of ordinary skill in the requisite art at the time of the invention of the invention was made would form a solder layer by using eutectic solder paste in process of Chiu et al. as taught by Rinne because the process would provide a high performance solder bump, also determining the optimum material for the layer only involved routine skill in the art.

The thickness range of the metal layers and the dry films are considered to involve routine optimization while has been held to be within the level of ordinary skill in the art. As noted in In re Aller 105 USPQ233, 255 (CCPA 1955), the selection of reaction parameters such as temperature and concentration would have been obvious:

"Normally, it is to be expected that a change in temperature, or in concentration, or in both, would be an unpatentable modification. Under some circumstances, however, changes such as these may impart patentability to a process if the particular ranges claimed produce a new and unexpected result which is different in kind and not merely degree from the results of the prior art...such ranges are termed "critical ranges and the applicant has the burden of proving such criticality.... More particularly, where the general conditions of a claim are disclosed in the prior art, it is not inventive to discover the optimum or workable ranges by routine experimentation."

In re Aller 105 USPQ233, 255 (CCPA 1955). See also In re Waite 77 USPQ 586 (CCPA 1948); In re Scherl 70 USPQ 204 (CCPA 1946); In re Irmscher 66 USPQ 314 (CCPA 1945); In re Norman 66 USPQ 308 (CCPA 1945); In re Swenson 56 USPQ 372 (CCPA

1942); In re Sola 25 USPO 433 (CCPA 1935); In re Dreyfus 24 USPO 52 (CCPA 1934).

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Therefore, one of ordinary skill in the requisite art at the time the invention was made would have used any thickness range suitable to the method in process of Chiu et al. in order to optimize the process.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Thanh Nguyen whose telephone number is (571) 272-1695, or by Email via address Thanh Nguyen@uspto.gov. The examiner can normally be reached on Monday-Thursday from 6:00AM to 3:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl Whitehead, Jr., can be reached on (571) 272-1702. The fax phone number for this Group is (703) 872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the Group receptionist whose telephone number is (703) 308-0956 (See MPEP 203.08).

Thanh Nguyen
Patent Examiner
Start Examining Group 28

Patent Examining Group 2800